



DOCUMENT CHANGE REQUEST

DCR number	686	Changes required for:	N/A	Originator:	Benoit Cornanguer
Date:	2011/12/06	Date sent:	2011/10/26	Organisation:	STMicroelectronics
Status:	IMPLEMENTED				

Title: TRANSISTORS, POWER, MOSFET, N-CHANNEL, RAD-HARD BASED ON TYPE STRH40N6

Number: 5205/024 Issue: 1

Other documents affected:

Page:

Pages 10 & 11

Paragraph:

Paragraph 2.4.1 Room Temperature Electrical Measurements

Original wording:

The limits of the AC test parameters [td(on)-tr-td(off)-tf] need to be updated as defined below:

td(on): maximum limit=21ns instead of 19ns

tr: maximum limit=92ns instead of 39ns

td(off): maximum limit=48ns instead of 27ns

tf: minimum limit=7ns instead of 10ns

tf: maximum limit=16ns instead of 15ns

Proposed wording:

Justification:


The ESCC detail specification has been written from the characterization results.

All AC electrical test parameters during the characterization phase have been done near of the body of the SMD.5 package.

Unlike for the ESCC qualification we have used a test socket; in this case we lost performance for the switching times and gate charge due to that the measurements are done more far of the body of the package.

If we take into account this statement, we are sure to cover all customer applications by giving to them the worst limits.

(This is not the case if we keep the limits defined after the characterization).

Attachments:
N/A
Modifications:
N/A
Approval signature:

Date signed:
2011-12-06